



# Automated Test Summit 08

A Virtual Industry Event Hosted by National Instruments



Time (CDT)	Event	Speaker
11:00 a.m.–6:00 p.m.	Exhibit Hall Open for Live Chat	
11:00 a.m.	<b>Keynote: Five Trends in Automated Test</b>	Mike Santori National Instruments
	<b>Reducing Software Development Costs</b>	
11:30 a.m.	Implementing Parallel Test Architectures	Craig Anderson National Instruments
	The Challenge of Requirements Management	Eric Larronde-Larretche Geensys
	Fundamentals of a Solid Software Design	Patrick Kelly Cal-Bay Systems, Inc.
	Improving Benchtop Measurement Productivity through Automation	Christopher J. Loberg Tektronix
	<b>Optimizing Automated Test Systems</b>	
12:30 p.m.	Why Choose a Modular Test Platform	Travis White National Instruments
	Designing Hybrid Systems with Multiple Instrument Control Buses	Murali Ravindran National Instruments
	Designing Custom Instrumentation	John Hottenroth National Instruments
1:30 p.m.	Break	
2:30 p.m.	<b>Regional Keynote: Addressing the Challenge of Multicore Programming (Americas and Asia)</b>	Jim St. Leger, Technical Marketing Manager, Intel  John Pasquarette, Director of Software Marketing, National Instruments
	<b>Regional Keynote: Ideal Test Systems for the Automotive Industry (Europe)</b>	Matthias Krause, President, CGS Automotive, Inc
	<b>Extending the Life of Your Automated Test System</b>	
3:00 p.m.	Building High Availability PXI Systems	Jennifer Schwartz National Instruments
	Mitigating Obsolescence with Hardware Abstraction Layers (HAL)	Nathan Tacha National Instruments
	Guarantee Long-Term Accuracy with Calibration	Chad Pelletier National Instruments
	Updating Deployed Test Systems	Andy Long Cyth Systems
	<b>The Test Engineering Panel</b>	
4:00 p.m.	Inserting Test Engineering in the Design Cycle	Andrew Mierau National Instruments
	Enhancing Your Test Engineering Team	Dean Streck VI Engineering
	Optimizing Test System Management: A Global Approach	Jean-Levy Beaudoin Averna
	Developing a Test Strategy Based on Product Mix and Volume	Marcus Gavin National Instruments



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11:00 a.m. CDT

## **Keynote: Five Trends in Automated Test**

Mike Santori, Technology and Business Fellow, National Instruments

11:30 a.m. CDT

## **Reducing Software Development Costs**

Software development offers some of the greatest cost-cutting potential in the automated test system development process. You can reduce software development costs by implementing a maintainable and scalable software architecture. In addition, other tools such as requirements management and benchtop measurement automation can help increase your productivity and reduce costs in the product design phase. Learn how you can reduce the cost of test by exploring the following topics:

- **Implementing Parallel Test Architectures** – Craig Anderson, National Instruments
- **The Challenge of Requirements Management** – Eric Larronde-Larretche, Geensys
- **Fundamentals of a Solid Software Design** – Patrick Kelly, Cal-Bay Systems, Inc.
- **Improving Benchtop Measurement Productivity through Automation** – Christopher J. Loberg, Tektronix

12:30 p.m. CDT

## **Optimizing Automated Test Systems**

A common challenge with managing automated test equipment is balancing a system's cost/performance ratio in addition to ensuring system longevity and flexibility to add new technologies. With a well-defined modular architecture, hybrid systems help you integrate newer technologies with older hardware and software to maximize your existing investments. In addition to hybrid test system design best practices, learn ways to achieve more efficient instrument usage and power consumption as well as techniques for creating custom instrumentation.

- **Why Choose a Modular Test Platform** – Travis White, National Instruments
- **Designing Hybrid Systems with Multiple Instrument Control Buses** – Murali Ravindran, National Instruments
- **Designing Custom Instrumentation** – John Hottenroth, National Instruments

2:30 p.m. CDT

## **Regional Keynote: Addressing the Challenge of Multicore Programming (Americas and Asia)**

Jim St. Leger, Technical Marketing Manager, Intel

John Pasqualette, Director of Software Marketing, National Instruments

## **Regional Keynote: Ideal Test Systems for the Automotive Industry (Europe)**

Matthias Krause, President, CGS Automotive, Inc

3:00 p.m. CDT

## **Extending the Life of Your Automated Test System**

Downtime caused by test systems often results in lost company revenue, especially in areas such as manufacturing. Because all electronic and automation devices have a finite lifetime, it is important to understand the availability (uptime) requirements of your applications. Learn best practices for maximizing your system uptime including techniques for effective obsolescence management and system calibration.

- **Building High-Availability PXI Systems** – Jennifer Schwartz, National Instruments
- **Mitigating Obsolescence with Hardware Abstraction Layers (HAL)** – Nathan Tacha, National Instruments
- **Guarantee Long-Term Accuracy with Calibration** – Chad Pelletier, National Instruments
- **Updating Deployed Test Systems** – Andy Long, Cyth Systems

4:00 p.m. CDT

## **The Test Engineering Panel**

Explore some of the common challenges test engineers face and learn how National Instruments and its partners have overcome these challenges with product life-cycle management, effective global test systems maintenance, standardization techniques, and more.

- **Inserting Test Engineering in the Design Cycle** – Andrew Mierau, National Instruments
- **Enhancing Your Test Engineering Team** – Dean Streck, V I Engineering
- **Optimizing Test System Management: A Global Approach** – Jean-Levy Beaudoin, Avera
- **Developing a Test Strategy Based on Product Mix and Volume** – Marcus Gavin, National Instruments